Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/748,152	LEE ET AL.	
Examiner	Art Unit	
Yonel Beaulieu	3661	

SEARCHED				
Class	Subclass	Date	Examiner	
701	41-42	8/26/2005	YB	
180	6.2	8/26/2005	YB	
	6.6			
280	1.202	8/26/2005	YB	
475	18-19	8/26/2005	YB	
477	1	8/26/2005	YB	
180	443	8/26/2005	YB	
702	127	8/26/2005	YB	
	150-151			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
WEST	8/26/2005	YB	
Inventor's Name Search	8/26/2005	YB	